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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/604,613	08/05/2003	Chiu-Tsung Huang	11039-US-PA	1612
31561	7590 10/04/2004		EXAMINER	
JIANQ CHYUN INTELLECTUAL PROPERTY OFFICE			TRAN, TAN N	
7 FLOOR-1, NO. 100 ROOSEVELT ROAD, SECTION 2 TAIPEI, 100 TAIWAN			ART UNIT	PAPER NUMBER
			2826	
			DATE MAILED: 10/04/2004	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
	10/604,613	HUANG ET AL.				
Office Action Summary	Examiner	Art Unit				
	TAN N TRAN	2826				
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address				
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	66(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	ely filed  will be considered timely. the mailing date of this communication.  (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on amendment filed on 08/19/04.						
2a) ☐ This action is FINAL. 2b) ☐ This	This action is FINAL. 2b) ☐ This action is non-final.					
	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under E	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims						
<ul> <li>4)  Claim(s) 13-19 is/are pending in the application 4a) Of the above claim(s) is/are withdray</li> <li>5)  Claim(s) is/are allowed.</li> <li>6)  Claim(s) 13-19 is/are rejected.</li> <li>7)  Claim(s) is/are objected to.</li> <li>8)  Claim(s) are subject to restriction and/or</li> </ul>	vn from consideration.					
Application Papers						
9) The specification is objected to by the Examine	r. ·					
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
Replacement drawing sheet(s) including the correcti  11) The oath or declaration is objected to by the Ex		· · · · · · · · · · · · · · · · · · ·				
Priority under 35 U.S.C. § 119						
<ul> <li>12) Acknowledgment is made of a claim for foreign a) □ All b) □ Some * c) □ None of:</li> <li>1. □ Certified copies of the priority documents</li> <li>2. □ Certified copies of the priority documents</li> <li>3. □ Copies of the certified copies of the priority application from the International Bureau</li> <li>* See the attached detailed Office action for a list of the priority documents</li> </ul>	s have been received. s have been received in Application ity documents have been receive (PCT Rule 17.2(a)).	on No ed in this National Stage				
Attachment(s)						
<ol> <li>Notice of References Cited (PTO-892)</li> <li>Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> </ol>	4) Interview Summary Paper No(s)/Mail Da					
3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  Paper No(s)/Mail Date		atent Application (PTO-152)				

#### **DETAILED ACTION**

### **Information Disclosure Statement**

1. If applicant is aware of any relevant prior art, he/she requested to cite it on form PTO-1449 in accordance with the guidelines set forth in M.P.E.P. 609.

## **Specification**

2. The title of the invention is still not descriptive. A new title is required that is clearly indicative of the invention to which the claims are directed.

## Claim Rejections - 35 USC § 102

3. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claims 13-19 stand rejected under 35 U.S.C. 102(a) as being anticipated by Lee et al. (2003/0042531).

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With regard to claims 13,14, Lee et al. discloses a memory having an insulation layer 22 disposed on the substrate layer 10; a silicon stripe layer 26 disposed on the insulation layer 22; a first control gate 36A and second control gate 36B disposed respectively on sidewalls of the silicon stripe layer 26; the source and drain regions formed in the silicon stripe layer 26 beside both sides of the first control gate 36A and second control gate 36B; oxide/nitride/oxide layer (42,40,44) disposed between the first control gate 36A and the silicon stripe 26 and between the second control gate 36B and silicon stripe 26. (Note see previous attachment #1, lines 3,4, paragraph 0058, page 2, fig. 6d of Lee et al.). It is inherent that oxide/nitride/oxide material (42,40,44) to be a silicon oxide/silicon nitride/silicon oxide mater because Lee et al's the structure is SONOS in order to obtain high K dielectric constant.

With regard to claims 15-19 Lee et al. discloses a memory having an insulation layer 22 disposed on the substrate layer 10; a silicon stripe layer 26 disposed on the insulation layer 22; a first control gate 36A and second control gate 36B disposed respectively on sidewalls of the silicon stripe layer 26; the source and drain regions formed in the silicon stripe layer 26 beside both sides of the first control gate 36A and second control gate 36B; a nitride layer 40 serves as a charge trapping layer disposed between the first control gate 36A and the silicon stripe layer 26 and between the second control gate 36B and the silicon stripe layer 26; a first dielectric layer 42 disposed between the nitride layer 40 and the silicon stripe layer 26; and a second dielectric layer 44 disposed between the nitride layer 40 and the second control gate 36B. (Note see attachment #1, lines 3,4, paragraph 0058, page 2, fig. 6d of Lee et al.). It is inherent that oxide/nitride/oxide material (42,40,44) to be a silicon oxide/silicon nitride/silicon oxide mater because Lee et al's the structure is SONOS in order to obtain high K dielectric constant.

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## **Response to Arguments**

4. Applicant's arguments filed 08/19/04 have been fully considered but they are not persuasive.

It is argued, at pages 7,8 of the remarks, that "Lee substantially fails to teach or disclose a multi-level memory cell comprising at least a first control gate and a second control gate disposed respectively on sidewalls of the semiconductive strip"; "nowhere in Lee there is any disclosure describing the first control gate 36A and the second control gate 36B". However, see previous attachment #1, fig. 6d of Lee et al. do show a first control gate 36A and second control gate 36B disposed respectively on sidewalls of the silicon stripe layer 26. Moverover, in response to applicant's arguments, the recitation "a multi-level memory cell" has not been given patentable weight because the recitation occurs in the preamble. A preamble is generally not accorded any patentable weight where it merely recites the purpose of a process or the intended use of a structure, and where the body of the claim does not depend on the preamble for completeness but, instead, the process steps or structural limitations are able to stand alone. See In re Hirao, 535 F.2d 67, 190 USPQ 15 (CCPA 1976) and Kropa v. Robie, 187 F.2d 150, 152, 88 USPQ 478, 481 (CCPA 1951). Since claims 13,15 do recite at least a first control gate and a second control gate disposed respectively and separately on sidewalls of the semiconductive strip Applicant's claims 1 and 2 do not distinguish over Lee et al reference.

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**Conclusion** 

5. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time

policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from

the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the

mailing date of this final action and the advisory action is not mailed until after the end of the

THREE-MONTH shortened statutory period, then the shortened statutory period will expire on

the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be

calculated from the mailing date of the advisory action. In no event, however, will the statutory

period for reply expire later than SIX MONTHS from the date of this final action.

6. Any inquiry concerning this communication or earlier communication from the examiner

should be directed to Tan Tran whose telephone number is (571) 272-1923. The examiner can

normally be reached on M-F 8:30AM-5PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Nathan Flynn can be reached on (571) 272-1915. The fax phone numbers for the

organization where this application or proceeding is assigned are (703) 872-9306 for regular

communications and (703) 872-9306 for after final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is (703) 305-3900.

TT

Sep 2004

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Minhloan Tran
Primary Examiner
Art Unit 2826